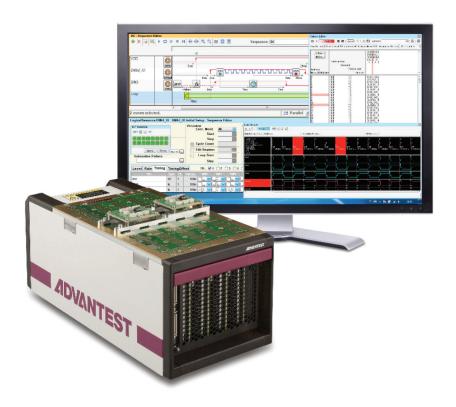**ADVANTEST**®

Digital Solution from R&D to Production

EVA100 MEASUREMENT SYSTEM

SINGLE SYSTEM COVERING R&D EVALUATION TO MASS PRODUCTION

Get your new devices to market faster with the EVA100 Digital Solution

- Compact, portable system with fully integrated digital IC testing capabilities
- Highly accurate timing synchronization and reliability boost evaluation efficiency
- Intuitive software interface does not require any specific skill set to operate the EVA100
- Total solution from R&D to production for better facility-wide communication

Getting to market quickly and reducing test costs are key requirements for consumer MCUs, IoT devices and SiPs, even high-mix products. The EVA100 Digital Solution is designed to meet customers' demands.

■ Portable system for digital IC evaluation

- 40% smaller than the initial EVA100 measurement system
- Integrates all needed measurement functions
- Standard software covers evaluation needs
- Able to hook and synchronize operations with external instruments

Feature

■ System module

- System bus control and synchronization
- Utility power supply
- Control of relays, I2C bus, external instrument control

■ Digital with analog, power supply function

- Digital I/O 256 ch/testing unit, 100-Mbps base rate
- Free-run clock feature with double clock mode
- 128-MW pattern memory, scan pattern
- Fail capture memory, digital capture memory
- High-voltage pin, per-pin PMU, TMU
- 18-bit AWG/DGT, VRef
- Device power supply 500 mA x N (gangable)
- Secondary device power supply (PDPS)

■ Software (Measurement Atelier)

- Pattern editor, logic analyzer tool
- Shmoo tool
- Report generator (automated report generating)
- Sequence gadget (test templates)
- Debug and evaluation tools

Specification

■ Size (testing unit)

- (W) 220 mm x (H) 206 mm x (D) 472 mm

■ Software (Measurement Atelier)

- Engineering model: 128 ch
- Production model: 256 ch, 512 ch, 768 ch, 1,024 ch

■ Expandable system covers a wide range of applications
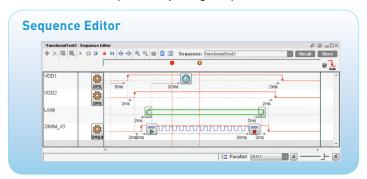
- Supports mixed-signal device testing

Target Devices

- IoT devices, MCUs
- DFT/BIST-driven devices
- Small FPGA/ASICs, fingerprint ICs, touch controllers
- SiP/module devices

Purpose

- R&D evaluation
- Wafer sort, package test, DFT testing
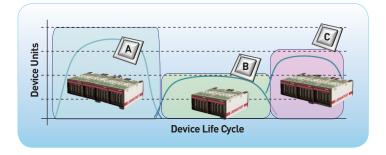- Package validation, IP validation, failure analysis
- System level test

■ Intuitive operation improves debugging efficiency

- No specific skill required to start using the EVA100
- Quick and easy operation with GUI tools
- Create test sequences by using templates

Sequence Editor

■ Scalable design for easy expansion

- Easily follow changes in production volume

![ADVANTEST]

ADVANTEST CORPORATION

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